

# TOKIN

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**TEST LAB.**

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## Technical Compliance Statement

No. ATM-E01021

The following products has been tested by us with the listed standards and found in compliance with the council EMC directive 89/336/EEC. It is possible to use CE marking to demonstrate the compliance with this EMC Directive.

**Submittor** : **FSP Group Inc.**  
**No. 22, Jianguo E, Rd.,**  
**Taoyuan City, Taiwan, R.O.C.**

**Product** : **Switching Power Supply**  
**M/N (1)ATX-300GN (2)ATX-300GT**

Test Standards	
EN 55022/1998	Limits and methods of measurement of radio disturbance characteristics of information technology equipment
EN 61000-3-2/1995 +A12/1996 +A13/1997 +A1/1998 +A2/1998+A14/2000	Part 3 : Limits -Section 2 : Limits for harmonic current emission (equipment input current $\leq 16A$ phase)
EN 61000-3-3/1995	Part 3 : Limits-Section 3 : Limitation of voltage fluctuations and flicker in low-voltage supply systems for equipment with rated current $\leq 16A$
EN 55024/1998	Information technology equipment-Immunity characteristics Limits and methods of measurement
	<b>IEC 61000-4-2/1995</b> Electrostatic discharge immunity test
	<b>IEC 61000-4-3/1995</b> Radiated, radio-frequency electromagnetic field immunity test
	<b>IEC 61000-4-4/1995</b> Electrical fast transient / burst immunity test
	<b>IEC 61000-4-5/1995</b> Surge immunity test
	<b>IEC 61000-4-6/1996</b> Immunity to conducted disturbances, induced by radio-frequency fields
	<b>IEC 61000-4-8/1993</b> Power Frequency Magnetic field immunity test
	<b>IEC 61000-4-11/1994</b> Voltage dips, short interruptions and voltage variations immunity test



  
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Jackie Deng  
Assistant G.M.

The verification is based on a single evaluation of one sample of above mentioned products. It does not imply an assessment of the whole production and does not permit the use of the test lab. logo.